MSKSEMI 美森科







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TSS



MOV



GDT



PIFD

MMBT2222AM3T5G-MS

Product specification





General Features

Epitaxial planar die construction
Complementary PNP Type available(MMBT2907AM)

Reference News

PACKAGE OUTLINE	Foot position analysis	Marking
WENEEM!	1. BASE 2.EMITTER 3.COLLECTOR	1P
SOT-723		



MAXIMUM RATINGS(Ta = 25°C)

Symbol	Parameter	Value	Unit
Vсво	Collector-Base Voltage	75	V
VCEO	Collector-Emitter Voltage	40	V
V EBO	Emitter-Base Voltage	6	V
lc	Collector Current -Continuous	0.5	Α
Pc	Power Dissipation	100	mW
R _{oja}	Thermal Resistance from Junction to Ambient	1250	°C/W
TJ	Junction Temperature	150	${\mathfrak C}$
Tstg	storage Temperature	-55~+150	${\mathfrak C}$

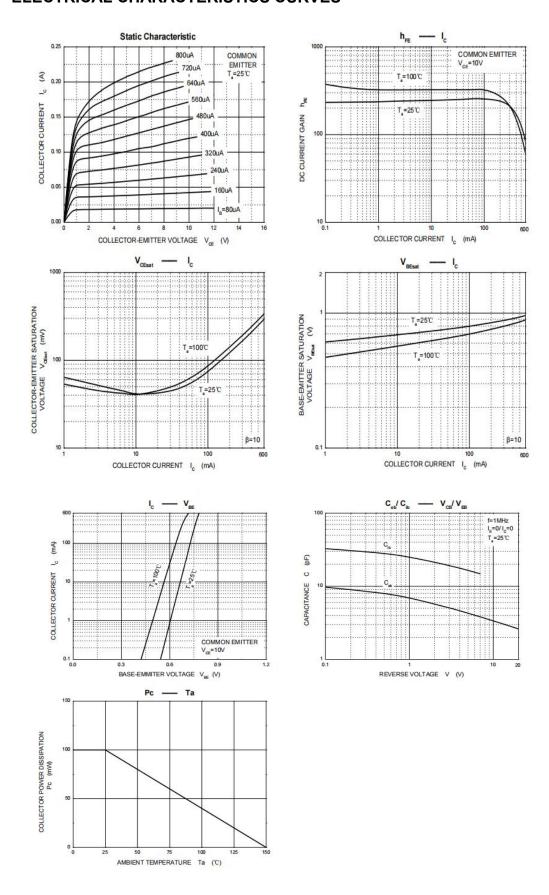
ELECTRICAL CHARACTERISTICS (Ta=25 ℃ unless otherwise

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =10pA, I _E =0	75			V
Collector-emitter breakdown voltage	V _{(BR)CEO} *	I _C =10mA, I _B =0	40			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =10pA, I _C =0	6			V
Collector cut-off current	Ісво	V _{CB} =60V, I _E =0			0.01	p _A
Collector cut-off current	Icex	V _{CE} =30V,V _{BE(off)} =3V			0.01	p _A
Emitter cut-off current	ІЕВО	V _{EB} =3V, I _C =0			0.01	p _A
		V _{CE} =10V, I _C = 150mA	100		300	
DC current gain	h _{FE} *	V _{CE} =10V, I _C = 0.1mA	40			
		V _{CE} =10V, I _C = 500mA	42			
Collector-emitter saturation voltage	V _{CE(sat)} *	I _C =500 mA, I _B = 50mA			1	V
	V CE(sat)	I _C =150 mA, I _B =15mA			0.3	V
Base-emitter saturation voltage	V _{BE(sat)} *	I _C =500 mA, I _B = 50mA			2.0	V
Ç		I _C =150 mA, I _B =15mA			1.2	V
Transition frequency	f _T	V _{CE} =20V, I _C = 20mA, f= 100MHz	300			MHz
Delay time	t _d	V _{CC} =30V, V _{BE(off)} =-0.5V			10	ns
Rise time	t _r	I _C =150mA , I _{B1} = 15mA			25	ns
Storage time	ts	Vcc=30V, Ic=150mA			225	ns
Fall time	t _f	- I _{B1} =-I _{B2} =15mA			60	ns

^{*}pulse test: Pulse Width ≤300ps, Duty Cycle≤ 2.0%.

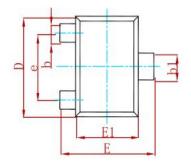


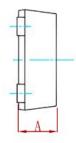
ELECTRICAL CHARACTERISTICS CURVES

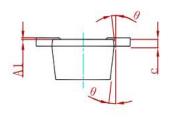




PACKAGE MECHANICAL DATA

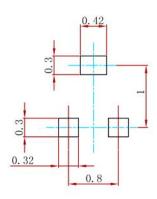






Symbol	Dimensions	In Millimeters	Dimensions	In Inches
	Min.	Max.	Min.	Max.
Α	0.430	0.500	0.017	0.020
A1	0.000	0.050	0.000	0.002
b	0.170	0.270	0.007	0.011
b1	0.270	0.370	0.011	0.015
С	0.080	0.150	0.003	0.006
D	1.150	1.250	0.045	0.049
E	1.150	1.250	0.045	0.049
E1	0.750	0.850	0.030	0.033
е	0 800	TYP	0 031	TYP
θ	7° F	REF.	7° R	EF.

Suggested Pad Layout



Note:

- 1. Controlling dimension: in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MMBT2222AM3T5G-MS	SOT-723	8000



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